



# ElectroMagnetic Field(EMF) Radiation Exposure TEST REPORT

No. I22Z60151-SEM01

For

**HONOR Device Co., Ltd.**

**Smart Phone**

**Model Name: LGE-NX9**

with

**Hardware Version: HN1LGEHM**

**Software Version: 6.0.0.108(C900E103R1P3)**

**FCC ID: 2AYGCLGE-NX9**

**Issued Date: 2022-4-27**

**Note:**

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

**Test Laboratory:**

CTTL, Telecommunication Technology Labs, CAICT

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## **REPORT HISTORY**

<b>Report Number</b>	<b>Revision</b>	<b>Issue Date</b>	<b>Description</b>
I22Z60151-SEM01	Rev.0	2022-4-27	Initial creation of test report



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## 1 Test Laboratory

### 1.1 Testing Location

Company Name:	CTTL(Shouxiang)
Address:	No. 51 Shouxiang Science Building, Xueyuan Road, Haidian District, Beijing, P. R. China100191

### 1.2 Testing Environment

Temperature:	Min. = 18°C, Max. = 25°C
Relative humidity:	Min. = 30%, Max. = 70%
Ground system resistance:	< 0.5 $\Omega$
Ambient noise & Reflection:	< 0.012 W/kg

### 1.3 Project Data

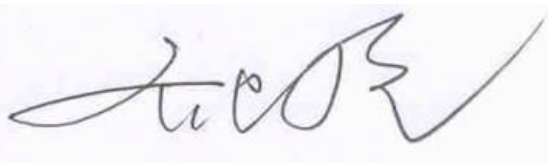
Project Leader:	Qi Dianyuan
Test Engineer:	Lin Xiaojun
Testing Start Date:	April 11, 2022
Testing End Date:	April 11, 2022

### 1.4 Signature



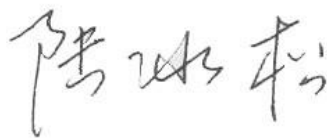
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Lin Xiaojun  
(Prepared this test report)



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Qi Dianyuan  
(Reviewed this test report)



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Lu Bingsong  
Deputy Director of the laboratory  
(Approved this test report)



## 2 Statement of Compliance

The maximum results of ElectroMagnetic Field (EMF) found during testing for HONOR Device Co., Ltd. Smart Phone LGE-NX9 is:

**E-field: 0.65V/m**

**H-field: 0.023A/m**

The E-field strength found for the Mobile Phone are below the maximum recommended levels of 614V/m according to the CFR47 1.1310.



### 3 Client Information

#### 3.1 Applicant Information

Company Name:	HONOR Device Co., Ltd.
Address/Post:	Shum Yip Sky Park, No. 8089, Hongli West Road, Shenzhen, China
Contact Person:	/
Contact Email:	/
Telephone:	/
Fax	/

#### 3.2 Manufacturer Information

Company Name:	HONOR Device Co., Ltd.
Address/Post:	Shum Yip Sky Park, No. 8089, Hongli West Road, Shenzhen, China
Contact Person:	/
Contact Email:	/
Telephone:	/
Fax	/

## 4 Equipment Under Test (EUT) and Ancillary Equipment (AE)

### 4.1 About EUT

Description:	Smart Phone
Model Name:	LGE-NX9
Tested mode:	Wireless Charging
Operating Frequency:	111–145 kHz
Test device Production information:	Production unit
Device type:	Portable device
Antenna type:	Integrated antenna
Hotspot mode:	Support

### 4.2 Internal Identification of EUT used during the test

EUT ID*	IMEI	HW Version	SW Version
EUT1	867843050038772/867843050039770	HN1LGEHM	6.0.0.108(C900E103R1P3)

\*EUT ID: is used to identify the test sample in the lab internally.

**Note:** It is performed to test E-field strength with the EUT1.

### 4.3 Internal Identification of AE used during the test

AE ID*	Description	Model	SN	Manufacturer
AE1	Battery	HB586680EFW	/	Honor Device Co., Ltd. (Factory: SUNWODA)
AE2	Battery	HB586680EFW	/	Honor Device Co., Ltd. (Factory: SCUD)
AE6	Headset	1331-3301-6001-TC-347	/	/

\*AE ID: is used to identify the test sample in the lab internally.

## 5 TEST METHODOLOGY

### 5.1 Applicable Measurement Standards

KDB 680106 D01 RF Exposure Wireless Charging Apps v03r01

### 5.2 RF Exposure Requirements

For devices designed for typical desktop applications, such as wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. Below 100 kHz, applicable reference levels for maximum instantaneous exposure field strengths are defined in clause 3.a).(2).

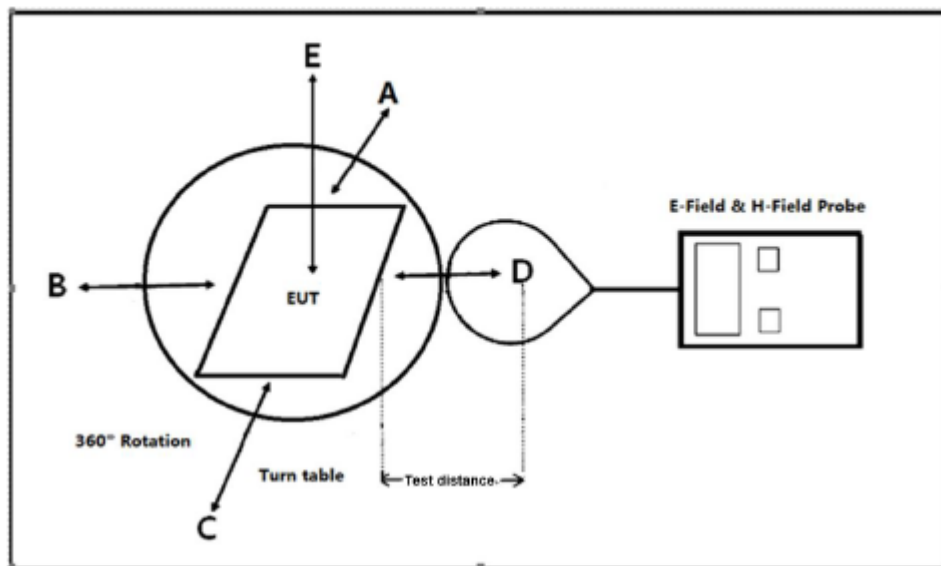
Table 1 to § 1.1310(e)(1) - Limits for Maximum Permissible Exposure (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm <sup>2</sup> )	Averaging time (minutes)
<b>(i) Limits for Occupational/Controlled Exposure</b>				
0.3-3.0	614	1.63	*(100)	≤6
3.0-30	1842/f	4.89/f	*(900/f <sup>2</sup> )	<6
30-300	61.4	0.163	1.0	<6
300-1,500			f/300	<6
1,500-100,000			5	<6
<b>(ii) Limits for General Population/Uncontrolled Exposure</b>				
0.3-1.34	614	1.63	*(100)	<30
1.34-30	824/f	2.19/f	*(180/f <sup>2</sup> )	<30
30-300	27.5	0.073	0.2	<30
300-1,500			f/1500	<30
1,500-100,000			1.0	<30

f = frequency in MHz. \* = Plane-wave equivalent power density.



## 6 Test Setup



### Measurement procedure:

Client device is placed directly in contact with the transmitter. The measurement probe was placed at test distance (10 cm) which is between the edge of the charger and the geometric center of probe. The turn table was rotated 360 degree to search of the highest strength.

The electric field strength measurement results at 10 cm from all applicable edges surrounding the DUT while it is actively charging the client device are performed. The highest emission level was recorded and compared with limit.

### DUT configuration:

- 1) The wireless charging operating frequency: 110 kHz-148 kHz
- 2) The wireless charging maximum output power: 7.5W
- 3) The transfer system includes only single primary coil. The device only support one-to-one pairing with the client device.
- 4) The client device should be placed directly in contact with the transmitter
- 5) The test results at three different charging conditions at 20%, 50% and 90% are included.

### 7 E-field strength Test Results

Charge amount	Distance(cm)	Test Position	Test Results(V/m)	Limit(V/m)	Remark
20%	10	Front Side	0.35	614	867843050038772
20%	10	Rear Side	0.54	614	867843050038772
20%	10	Left Side	0.45	614	867843050038772
20%	10	Right Side	0.43	614	867843050038772
20%	10	Top Side	0.42	614	867843050038772
20%	10	Bottom Side	0.37	614	867843050038772
50%	10	Front Side	0.38	614	867843050038772
50%	10	Rear Side	0.45	614	867843050038772
50%	10	Left Side	0.40	614	867843050038772
50%	10	Right Side	0.36	614	867843050038772
50%	10	Top Side	0.49	614	867843050038772
50%	10	Bottom Side	0.31	614	867843050038772
90%	10	Front Side	0.52	614	867843050038772
90%	10	Rear Side	<b>0.65</b>	614	867843050038772
90%	10	Left Side	0.48	614	867843050038772
90%	10	Right Side	0.47	614	867843050038772
90%	10	Top Side	0.42	614	867843050038772
90%	10	Bottom Side	0.23	614	867843050038772

### 8 H-field strength Test Results

Charge amount	Distance(cm)	Test Position	Test Results(A/m)	Limit(A/m)	Remark
20%	10	Front Side	0.006	1.63	867843050038772
20%	10	Rear Side	0.008	1.63	867843050038772
20%	10	Left Side	0.021	1.63	867843050038772
20%	10	Right Side	0.009	1.63	867843050038772
20%	10	Top Side	0.014	1.63	867843050038772
20%	10	Bottom Side	0.012	1.63	867843050038772
50%	10	Front Side	0.012	1.63	867843050038772
50%	10	Rear Side	0.009	1.63	867843050038772
50%	10	Left Side	0.015	1.63	867843050038772
50%	10	Right Side	0.010	1.63	867843050038772
50%	10	Top Side	0.018	1.63	867843050038772
50%	10	Bottom Side	0.009	1.63	867843050038772
90%	10	Front Side	0.018	1.63	867843050038772
90%	10	Rear Side	0.011	1.63	867843050038772
90%	10	Left Side	<b>0.023</b>	1.63	867843050038772
90%	10	Right Side	0.009	1.63	867843050038772
90%	10	Top Side	0.007	1.63	867843050038772
90%	10	Bottom Side	0.013	1.63	867843050038772

## ANNEX A Accreditation Certificate

United States Department of Commerce  
National Institute of Standards and Technology

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**Certificate of Accreditation to ISO/IEC 17025:2017**

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NVLAP LAB CODE: 600118-0

**Telecommunication Technology Labs, CAICT**  
Beijing  
China

*is accredited by the National Voluntary Laboratory Accreditation Program for specific services,  
listed on the Scope of Accreditation, for:*

**Electromagnetic Compatibility & Telecommunications**

*This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality  
management system (refer to joint ISO-ILAC-IAF Communiqué dated January 2009).*

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2021-09-29 through 2022-09-30  
*Effective Dates*



  
*For the National Voluntary Laboratory Accreditation Program*